

MS/RF PCM/PROCESS CHECKLIST WORKING GROUP MEETING MINUTES

Date: September 16, 2010
Location: Santa Clara Convention Center, Meeting Room #1
Time: 12:15-1:15pm (Pacific)
Participants:

Chelsea Boone – GSA
David Schwan – Independent Consultant
Larry Mehringer – Mehringer Consulting
Mei Zhu – Apple
Philippe Jansen – IMEC
Michel Bourdon – Altis Semiconductor
Sam Taheri – IP Semantics
KT Soon – ISE
Sergio Bampi – CEITEC S.A.

Meeting Purpose:

To make a decision on a measurement definition for each parameter description in the parameter list spreadsheet. We will not cover all parameter descriptions in one meeting. This will be an on-going process.

End Result/Conclusions:

- Per the working group's feedback, definitions were selected for various parameter descriptions. To view the definitions selected, please see Version 6 of the PCM parameter list at http://www.gsaglobal.org/ams/index_wg.aspx?tab=2 (under Resources).
- Next Meeting (November 2010): We will again continue to revise Version 6 and select the appropriate measurement definitions for parameter descriptions.